



Ultra-Fast Interconnect Driven Cell Cloning For Minimizing Critical Path Delay

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Best Value Toys



Global placement

Routability analysis / recovery

Buffering

Cell movement

Vt assignment

Gate Sizing

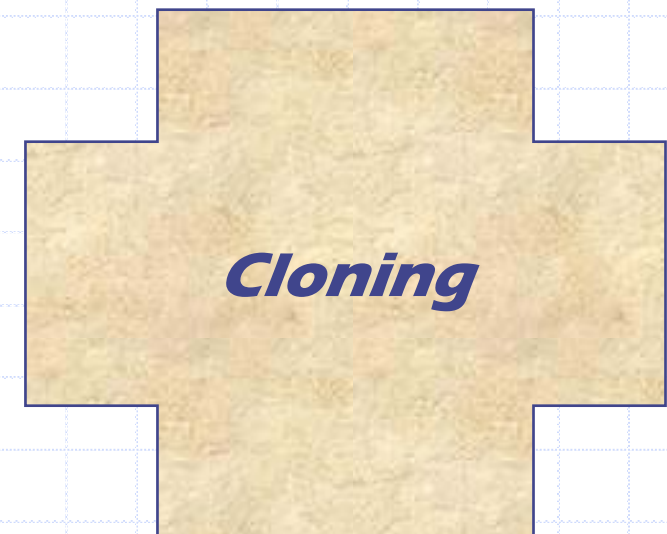
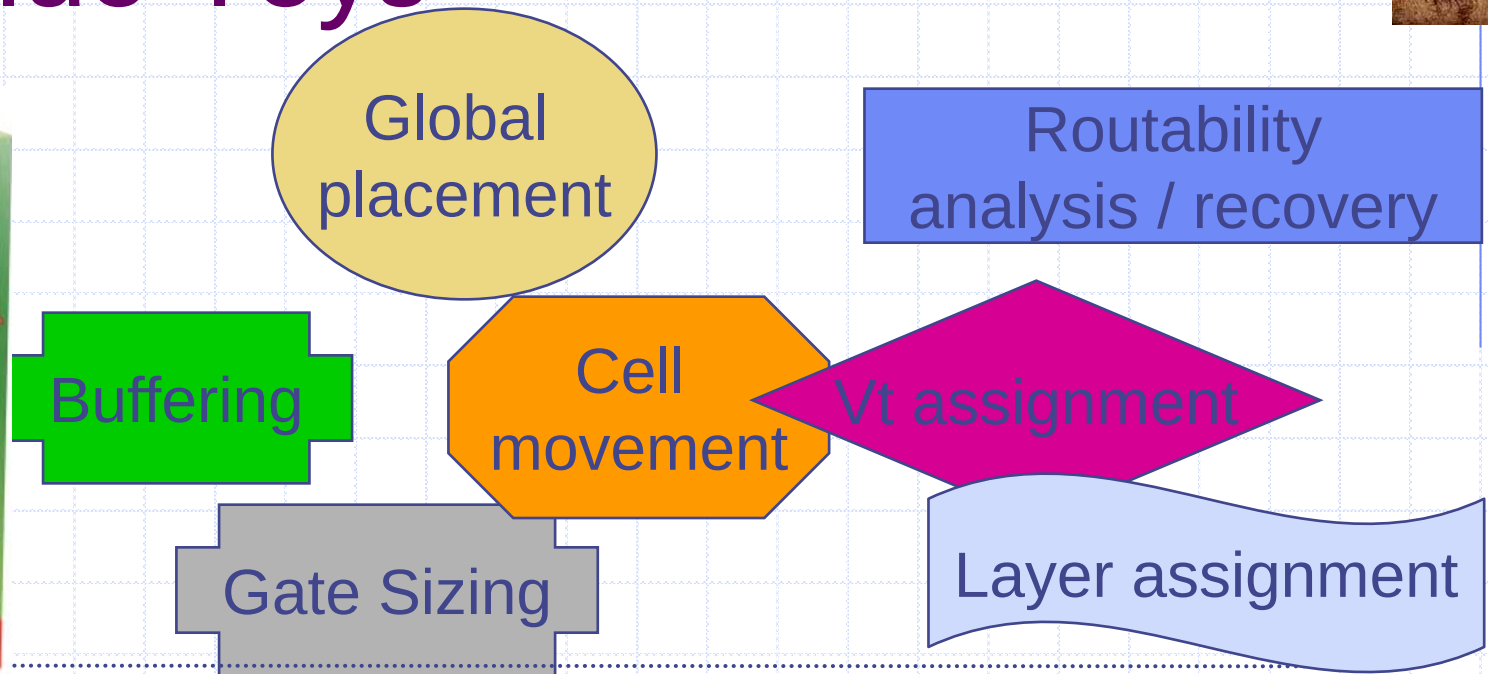
Layer assignment

\$15K



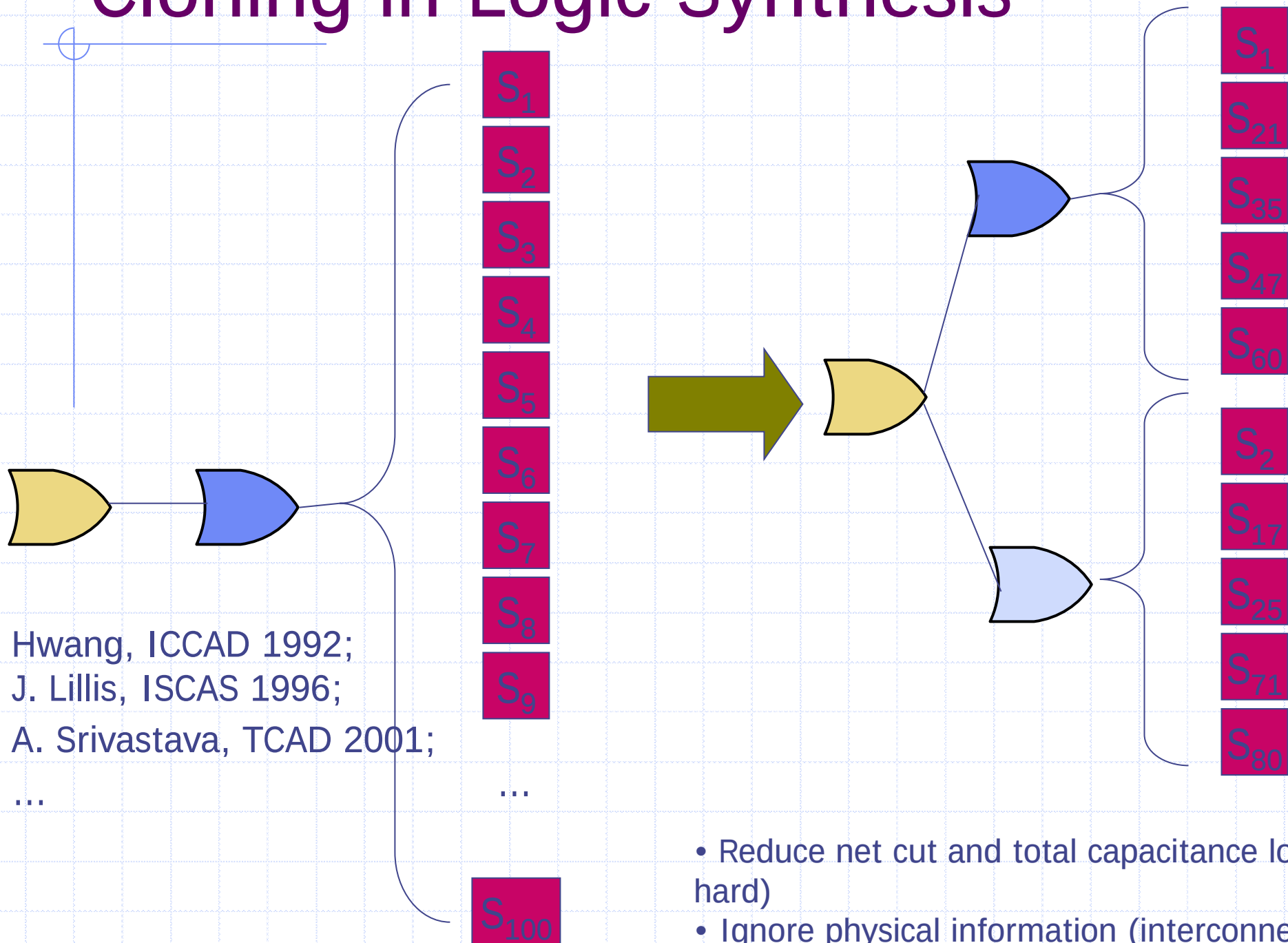
Cloning?

Best Value Toys





Cloning in Logic Synthesis

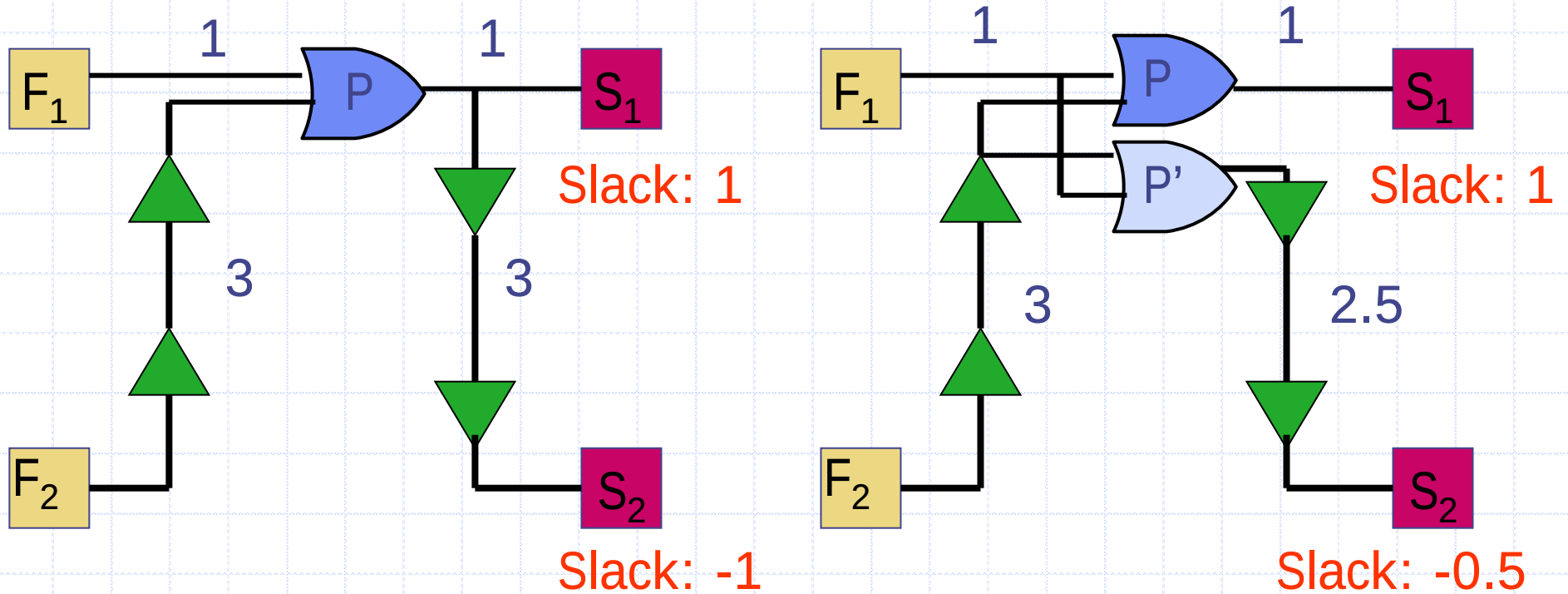


Hwang, ICCAD 1992;
J. Lillis, ISCAS 1996;
A. Srivastava, TCAD 2001;
...

- Reduce net cut and total capacitance load (NP-hard)
- Ignore physical information (interconnect, buffering, ...)

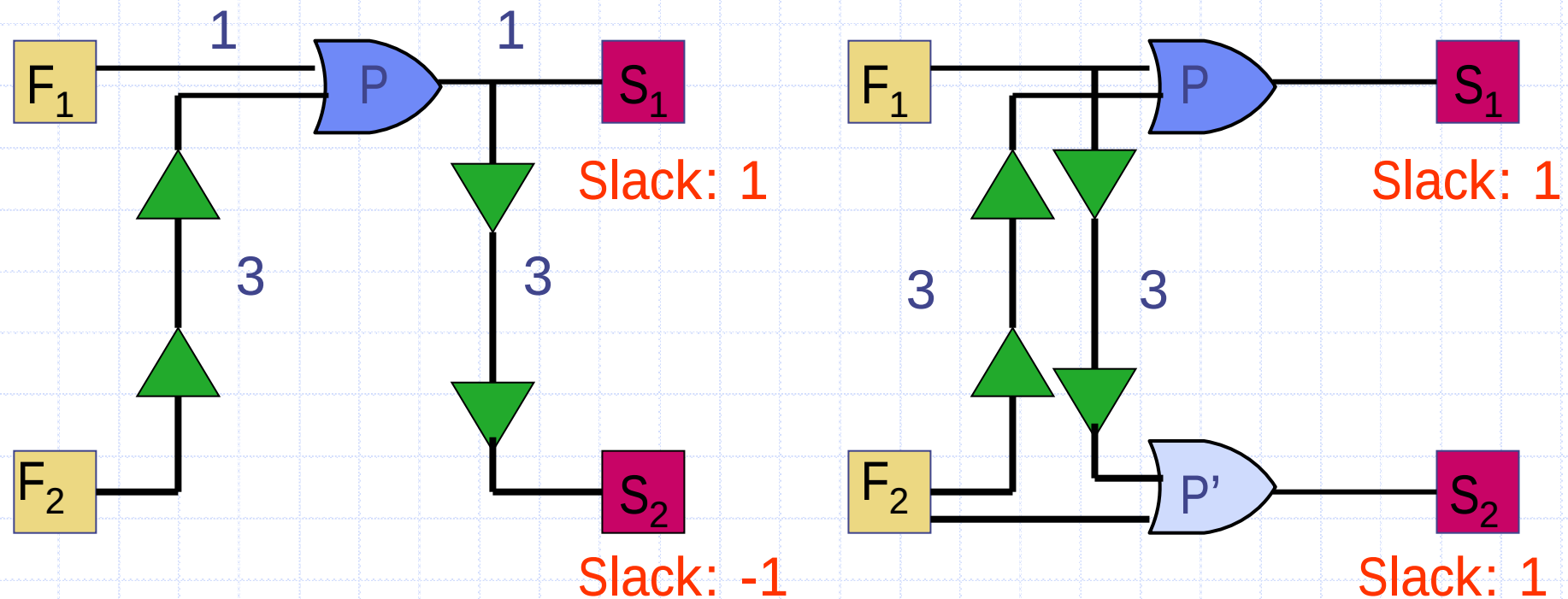


Interconnect Driven Cloning



$$AT(D_1) = AT(D_2) = 0 \quad RAT(S_1) = RAT(S_2) = 5$$

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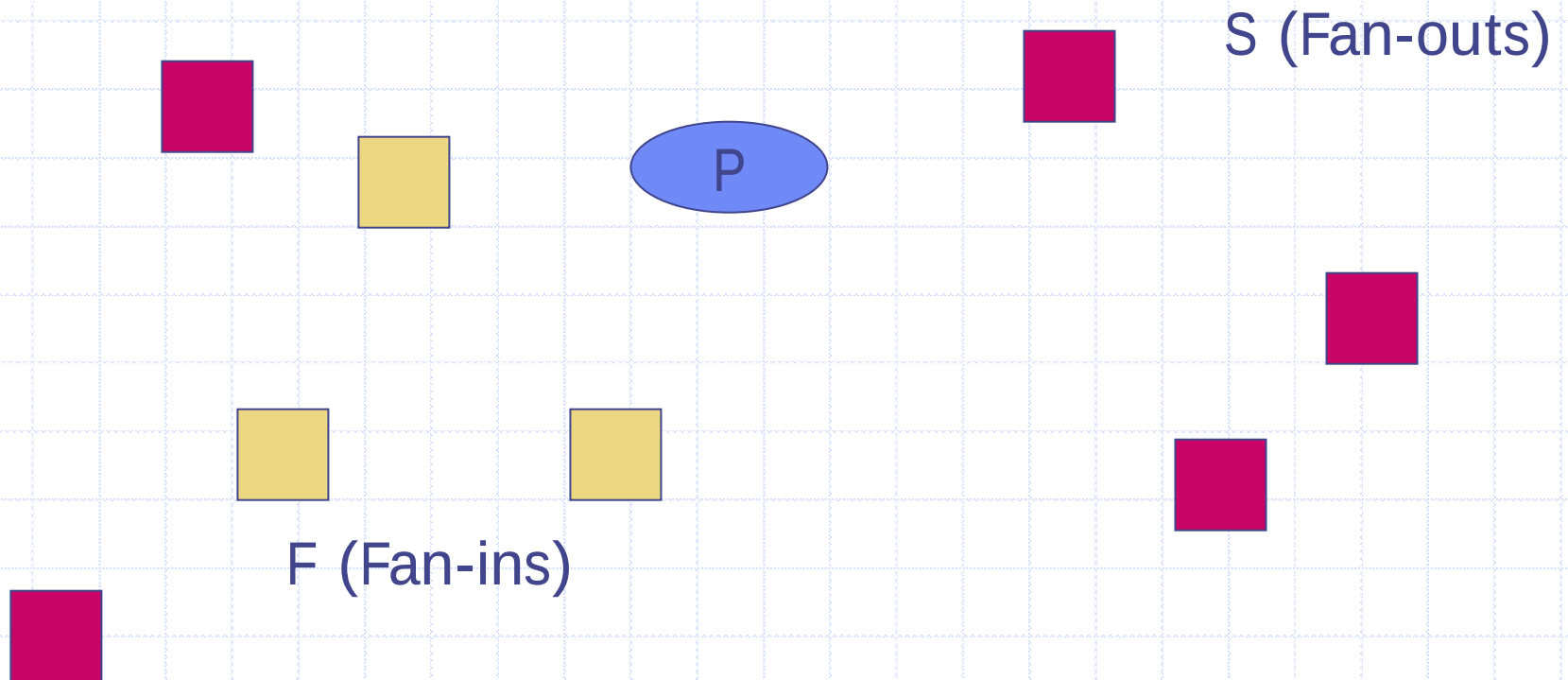
Our Contribution

- ◆ Find the “optimal” partitioning and placement of the original and duplicated gates
 - Assuming linear-buffer-delay model
 - $O(n)$ algorithm when original gate is fixed
 - $O(n \log n)$ algorithm when original gate is movable
 - Just focus on worst slack
 - For interconnect delay dominant sub-circuit
 - Extensions
- ◆ Back of envelop filter
 - Logic based cloning: High fan-outs/capacitive load
 - Physical based cloning: special fan-out location distributions



Cloning Problem

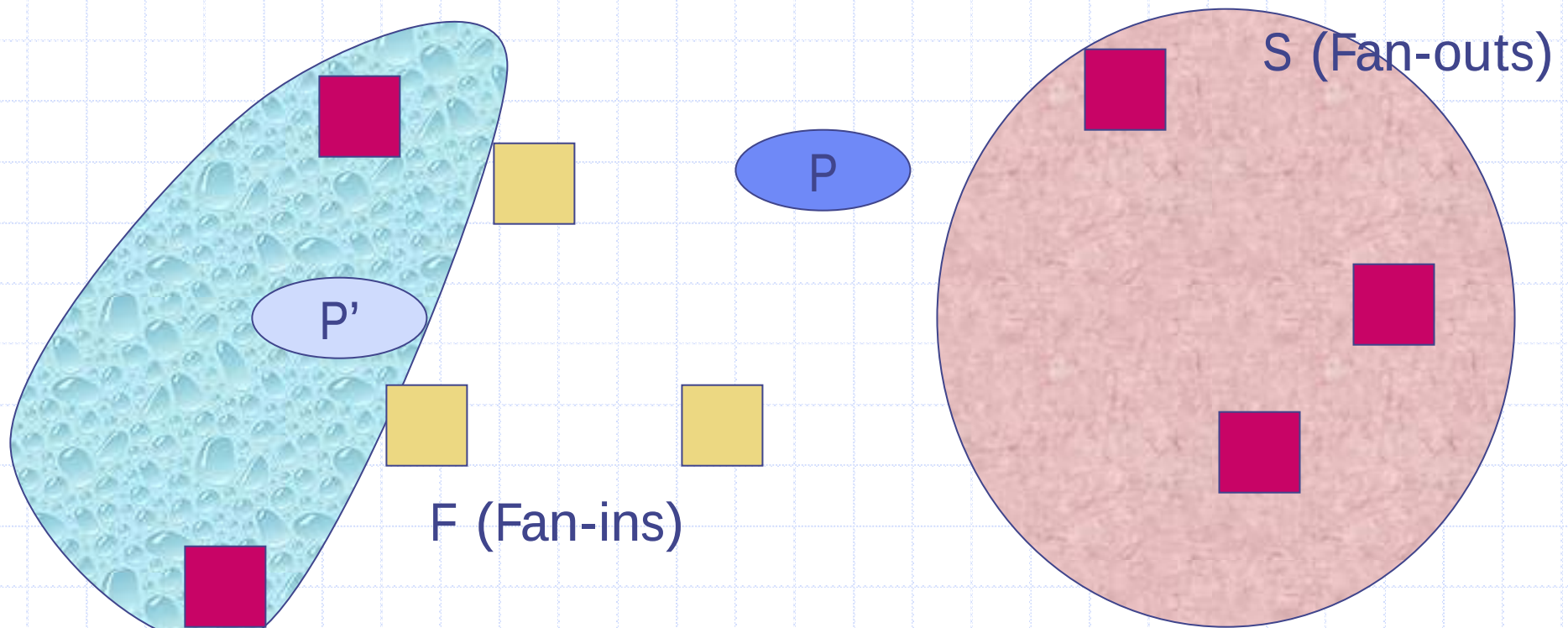
- ◆ A sub-circuit
- ◆ Two-pin timing arcs $D = \sigma \cdot \text{dis}(G_1, G_2)$
- ◆ Clone P to P' , find the partitioning of S and locations of P and P' , to maximize sub-circuit slack





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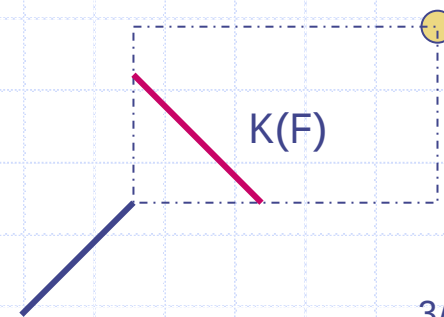
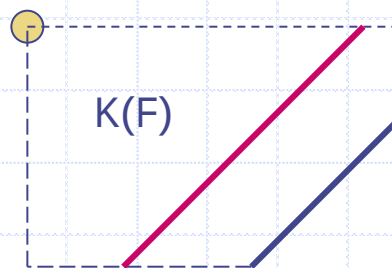
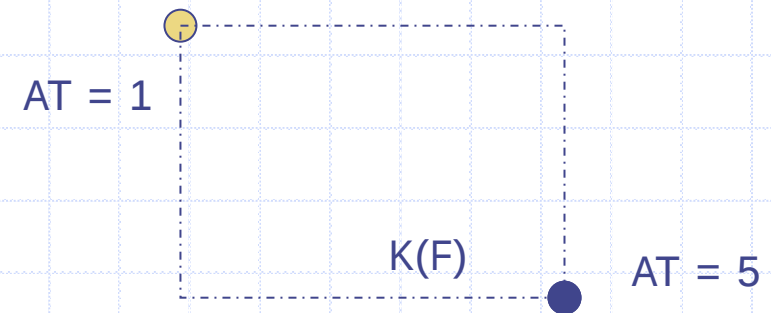
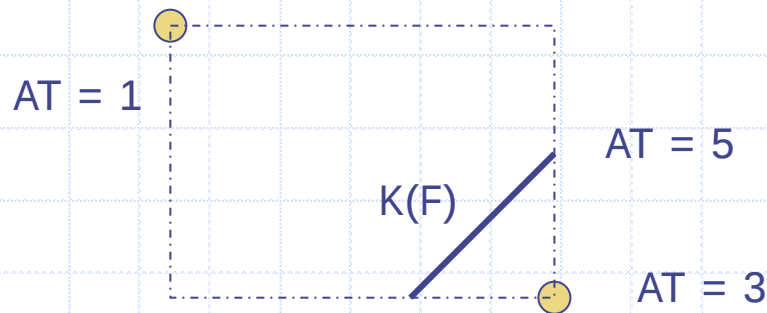
- # Fanouts





Arrival Time Arc

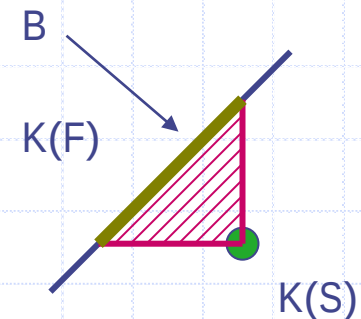
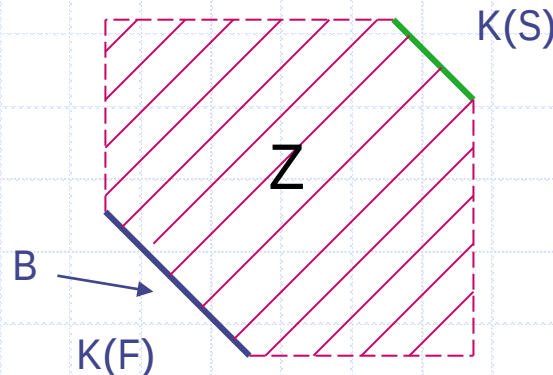
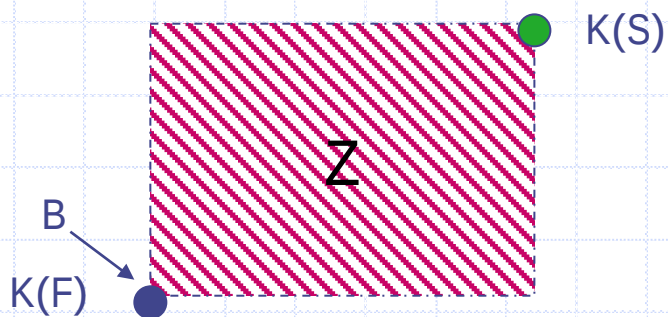
- ◆ Each fan-in gate has an arrival time $AT(F_i)$
- ◆ For each physical point v , $AT(v) = \max(AT(F_i) + \tau \cdot Dis(AT(F_i), v))$
- ◆ The set of points minimizing $AT(v)$ is **arrival time arc** $K(F)$
- ◆ $K(F)$ is either an Manhattan arc or a single point
- ◆ Similar to Deferred Merge Embedding (DME)
- ◆ $K(F)$ is also the bottom of a trough $AT(v)$ (overlapping of a set of reverse pyramids)





Best Region and Best Arrival Time Arc

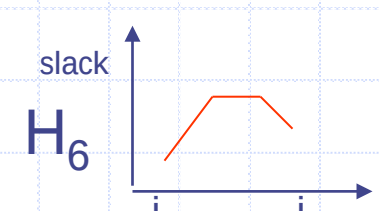
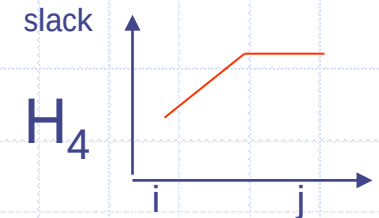
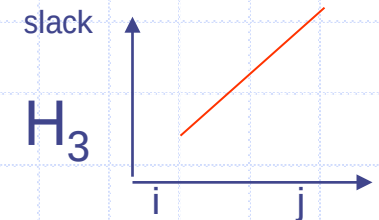
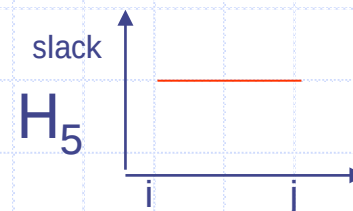
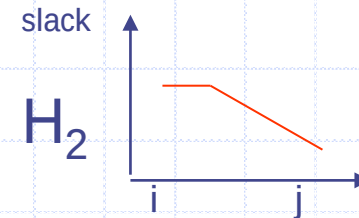
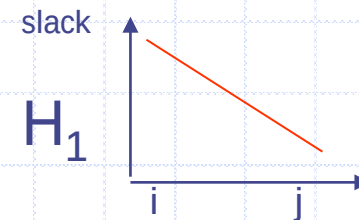
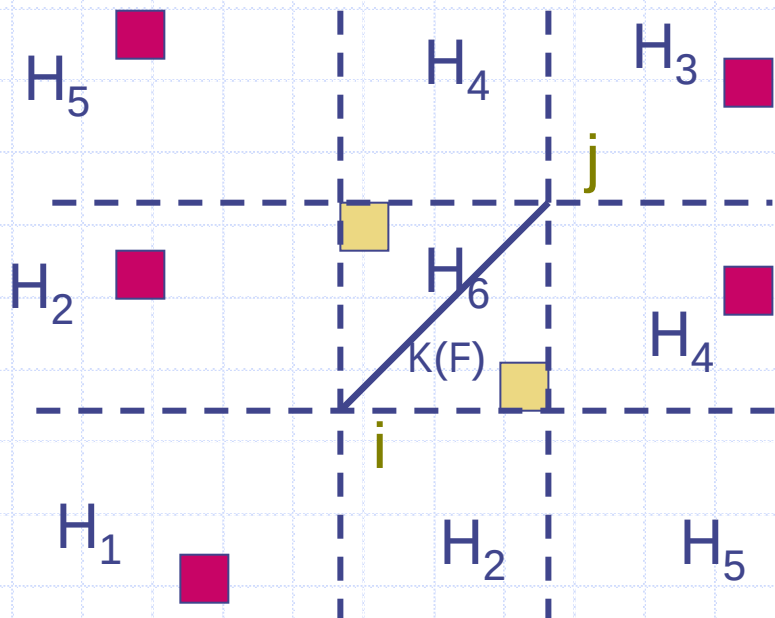
- ◆ $K(S)$: *required arrival time arc* (maximizing $RAT(v)$)
- ◆ **Best region Z** : every point inside this region has maximum sub-circuit slack (constructed with $K(F)$ and $K(S)$)
- ◆ **Best Arrival Time arc B** is the intersection of Best Region and Arrival Time Arc
- ◆ Define $K(F_i)$ as the arrival time arc for $F_1, \dots, F_i$
- ◆ $O(n)$ time to compute $K(F)$, $K(S)$, Z and B . Also $O(n)$ time to compute all $K(F_i)$ and $K(S_i)$, instead of $O(n^2)$ time.





Case 1: P is movable

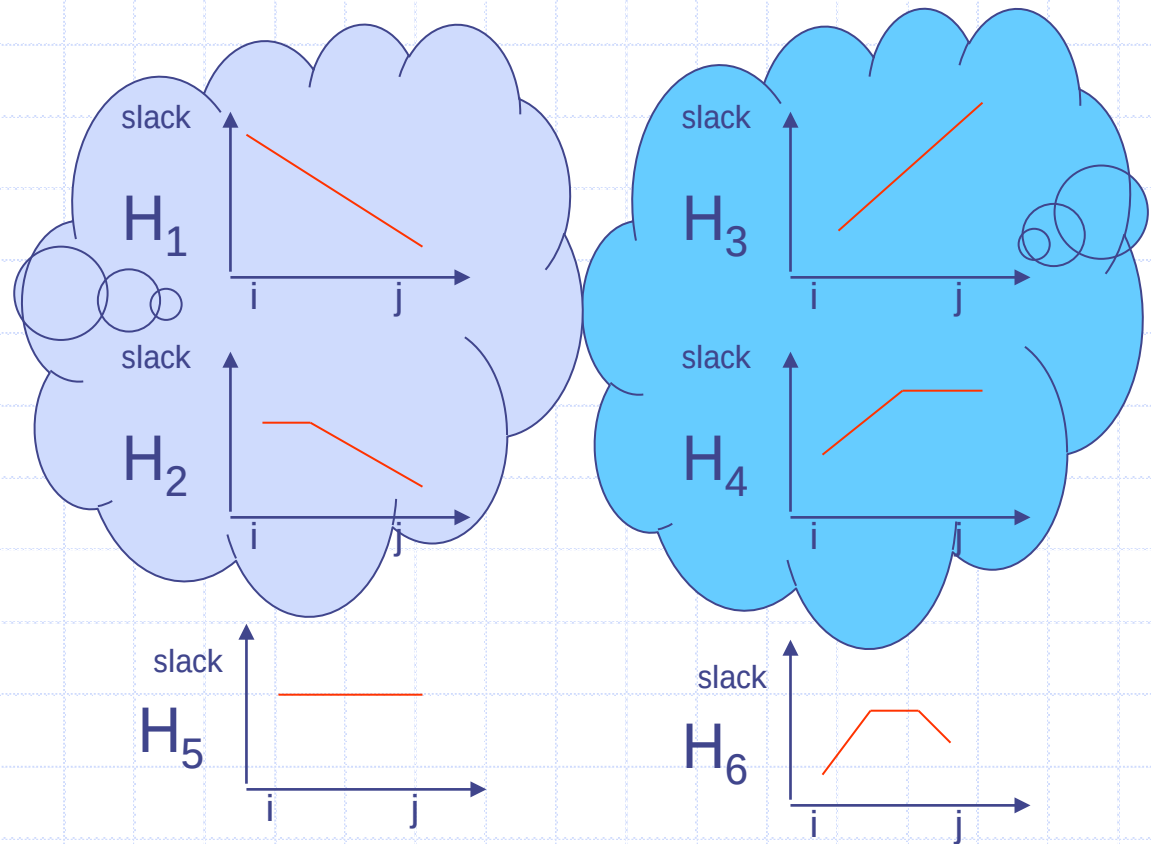
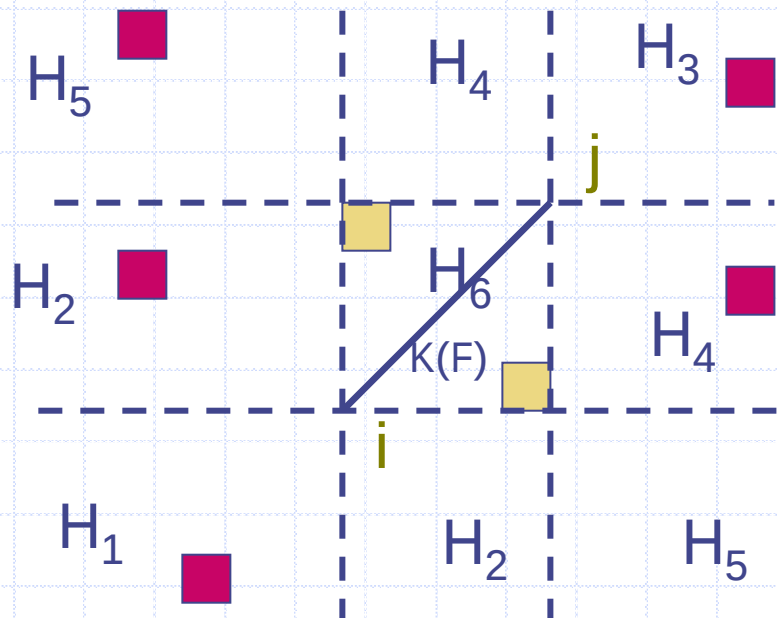
- ◆ No matter what the partitioning is, one can place P and P' on best arrival time arc, while still achieving the best slack
- ◆ Divide the whole plane into 6 regions based on slack curves





Case 1: P is movable (Cont.)

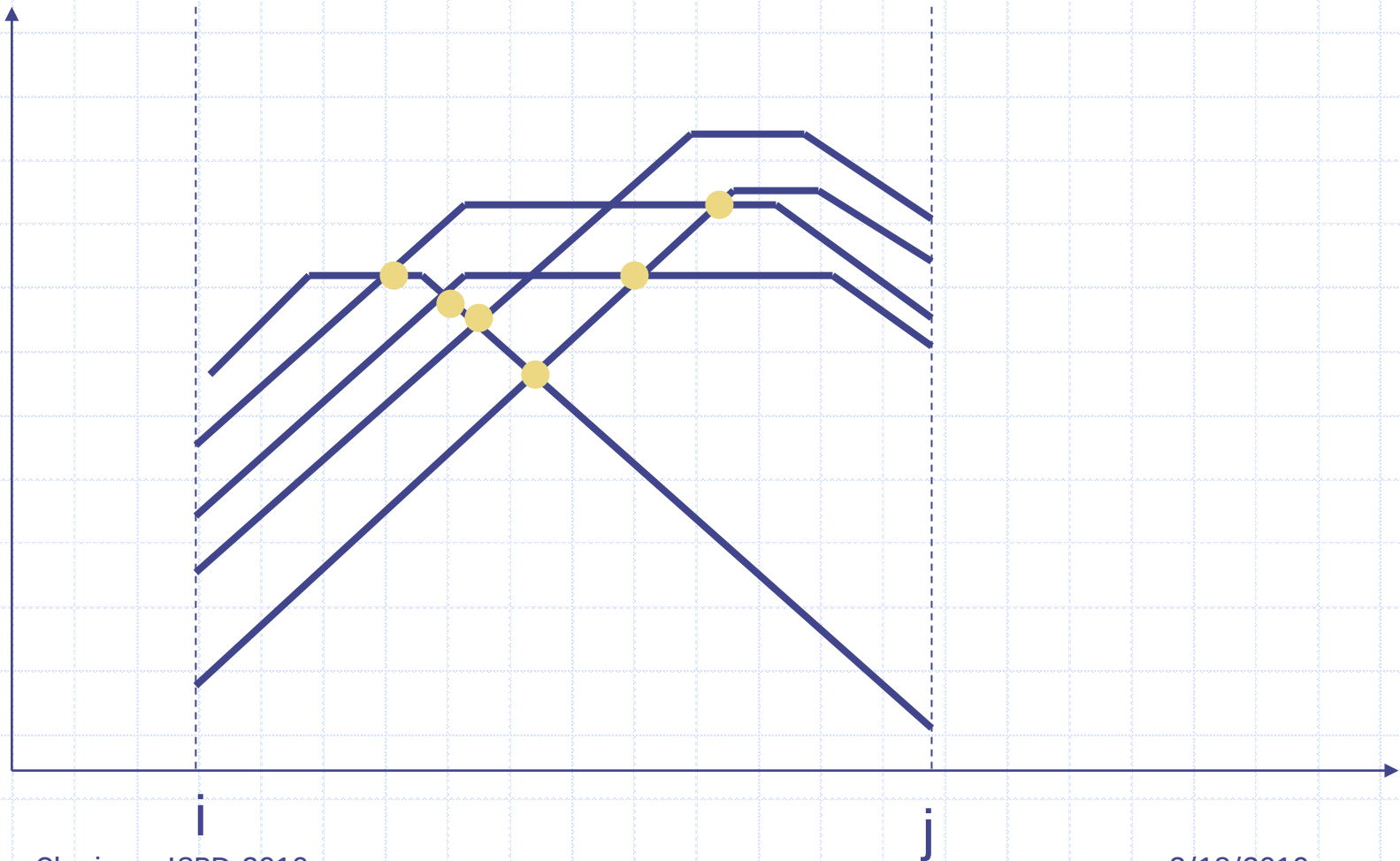
- ◆ If no gates in H_6 , $O(n)$ time algorithm





Case 1: P is movable (Cont.)

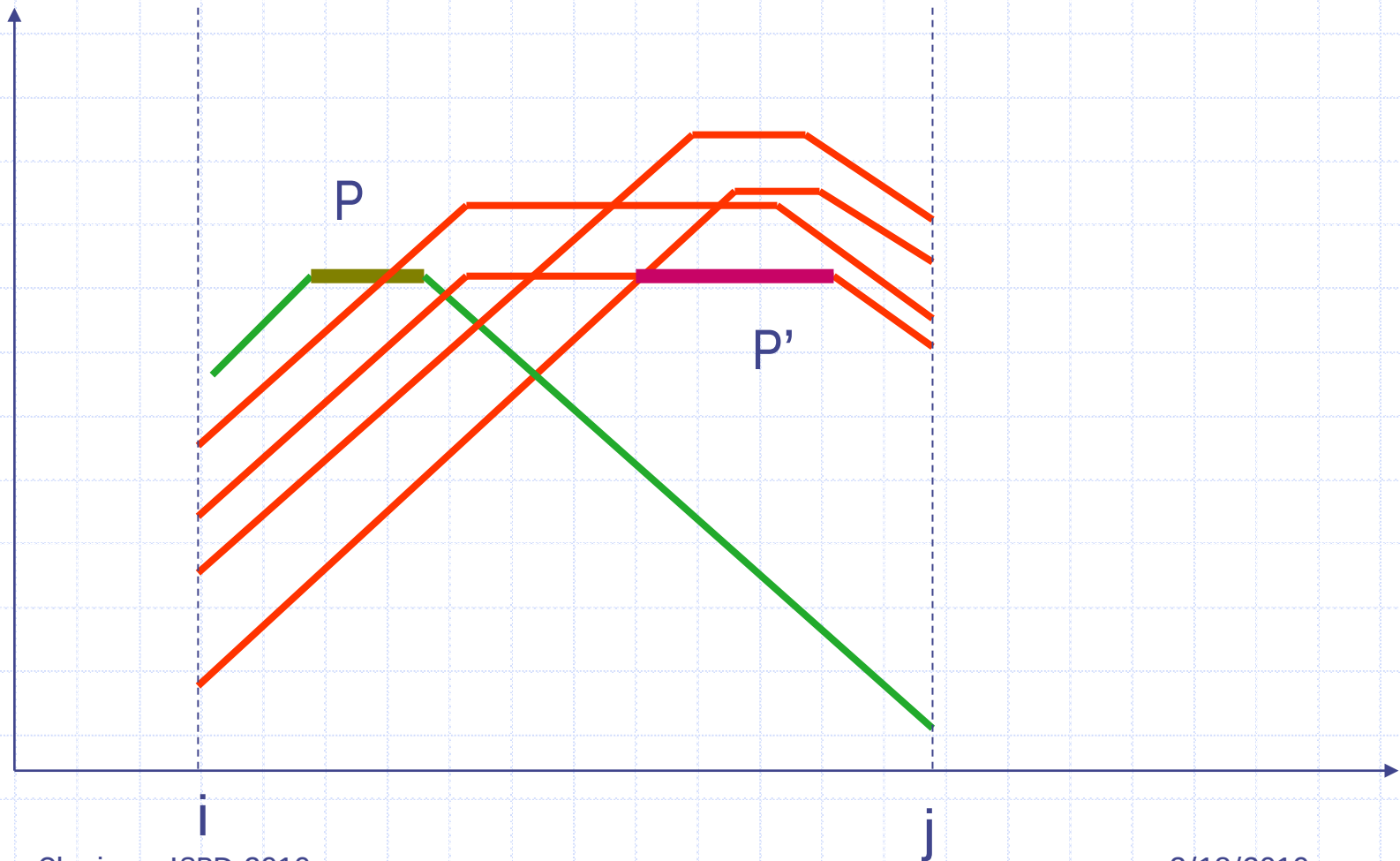
- ◆ If there are gates in H_6 , treat all slack curves as 3-segment trapezoid-like curves
- ◆ $O(n)$ time algorithm





Case 1: P is movable (Cont.)

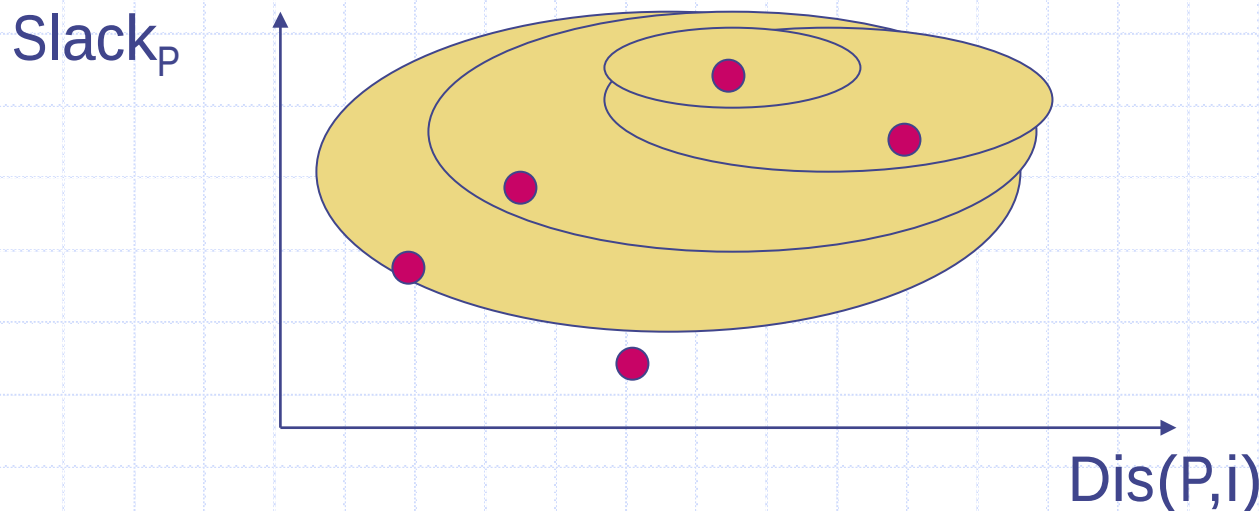
- ◆ If there are gates in H_6 , treat all slack curves as 3-segment trapezoid-like curves
- ◆ $O(n)$ time algorithm





Case 2: P is fixed

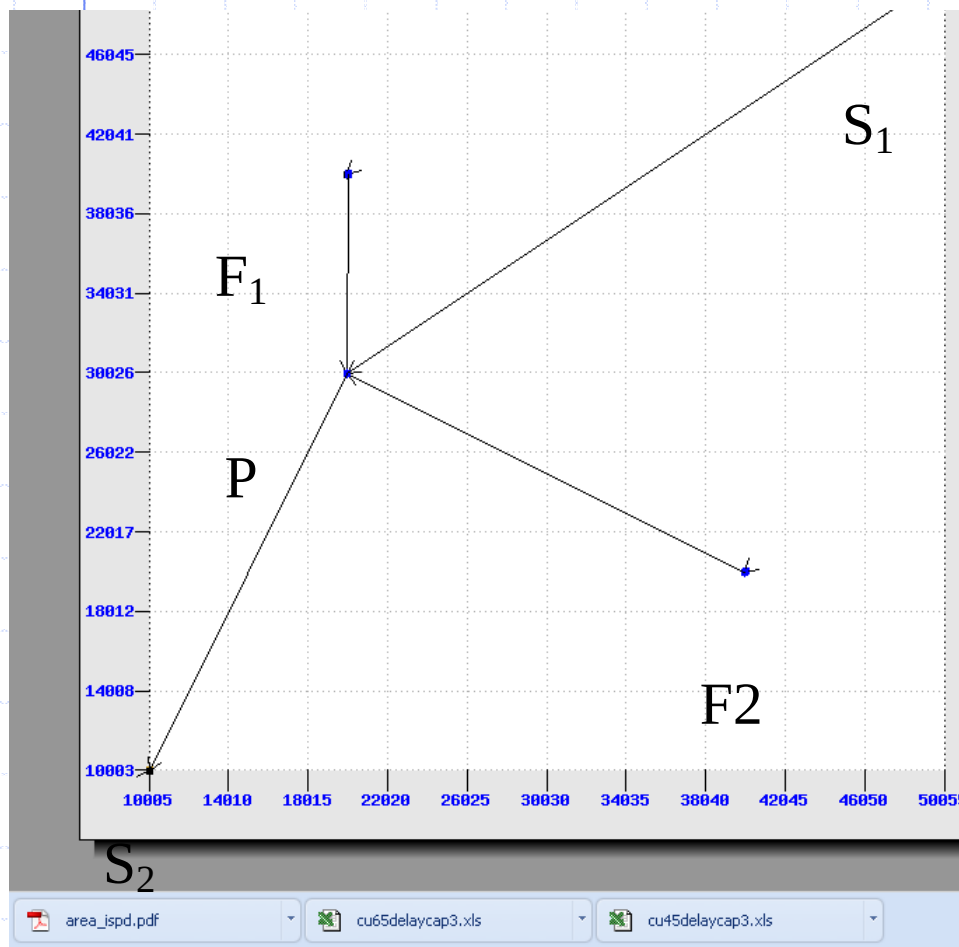
- ◆ P may not be on $K(F)$
- ◆ $Slack_P(i) = RAT(i) - \tau \cdot Dis(P, i) - AT(P)$
- ◆ At most $O(n)$ partitions since there are only n possible worst slack values for any partitioning
- ◆ Sort S_i accordingly
- ◆ Let P drive the set of fan-outs $\{S_1\}, \{S_1, S_2\}, \{S_1, S_2, S_3\}, \dots$
- ◆ $O(n \log n)$ time algorithm



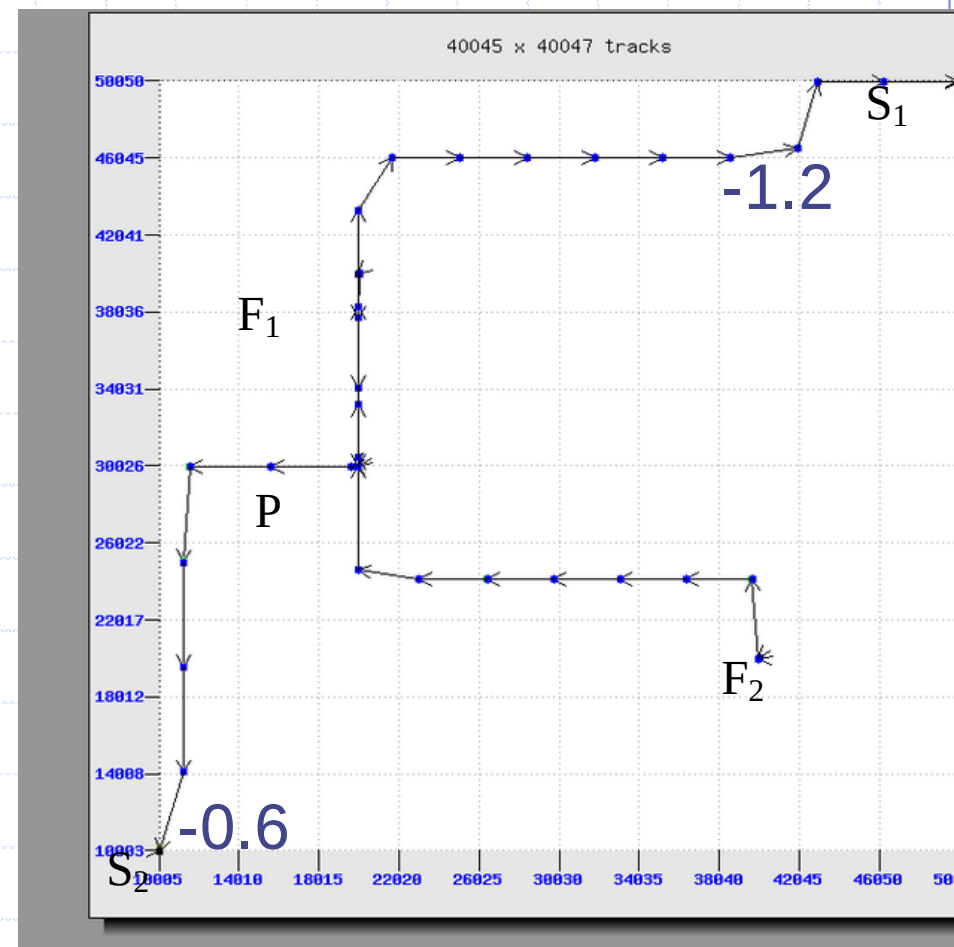


One Example

Original circuit



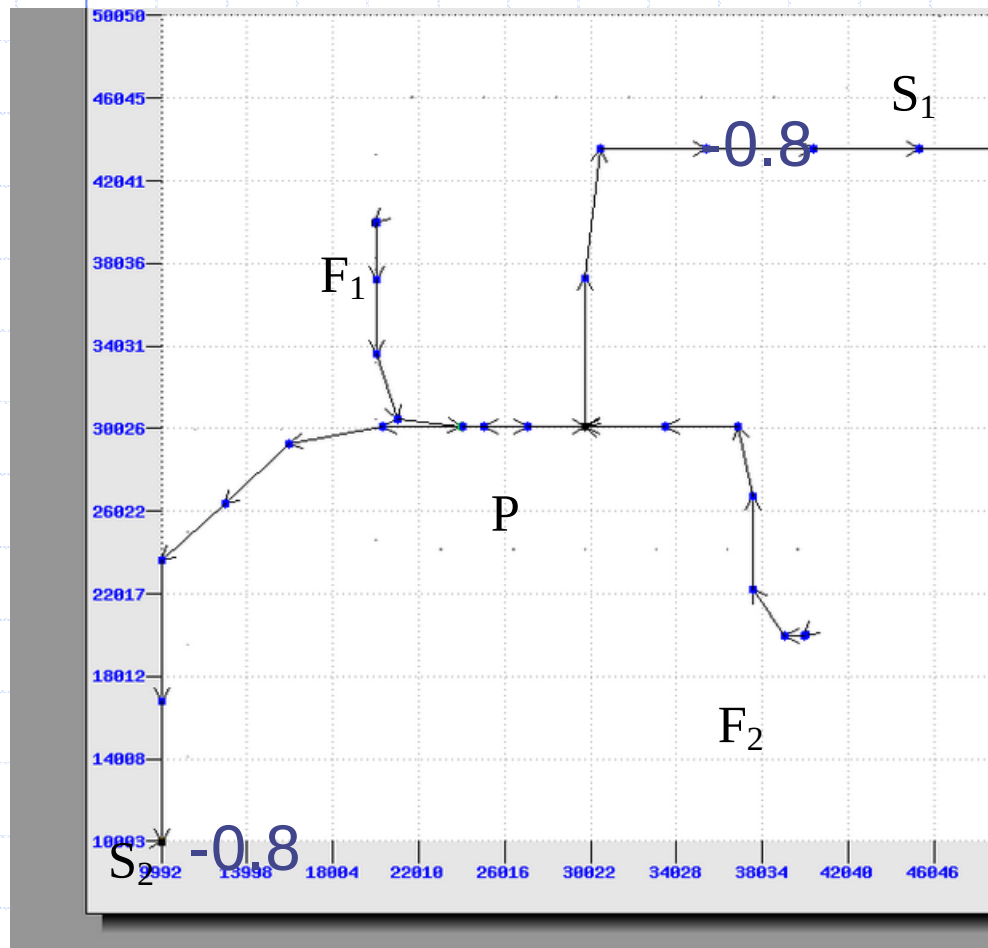
After buffering



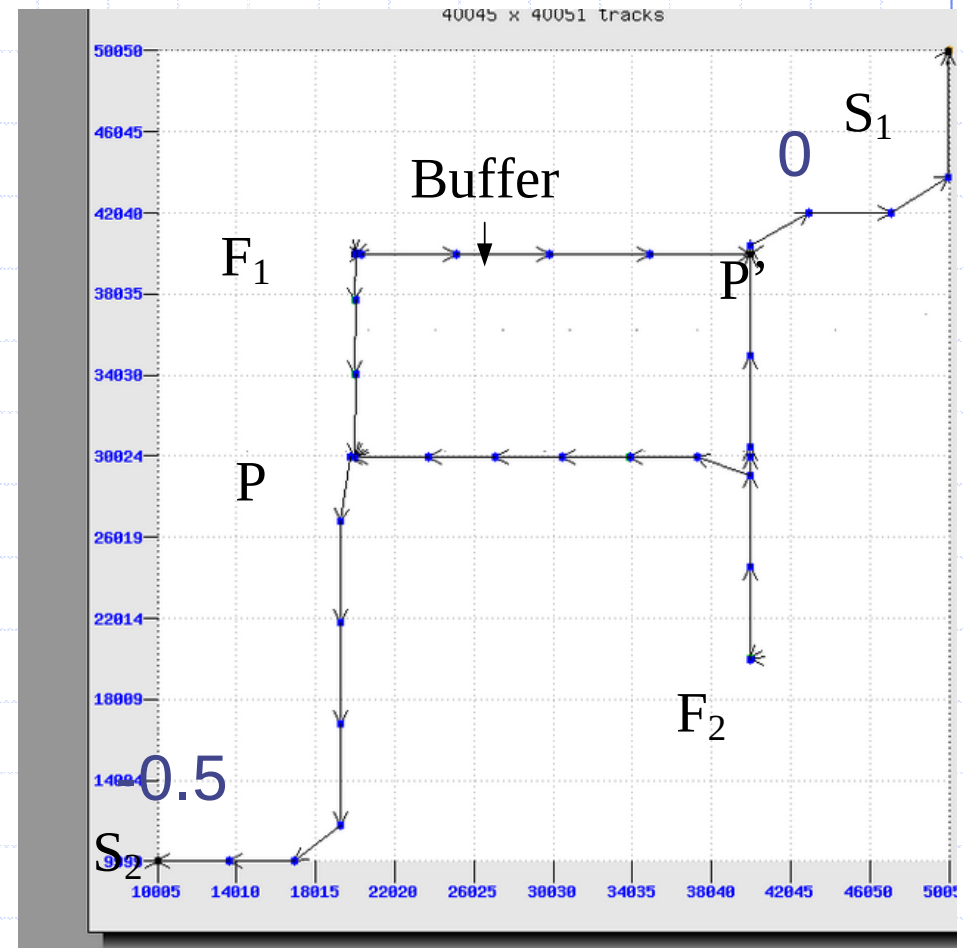


One Example

RUMBLE



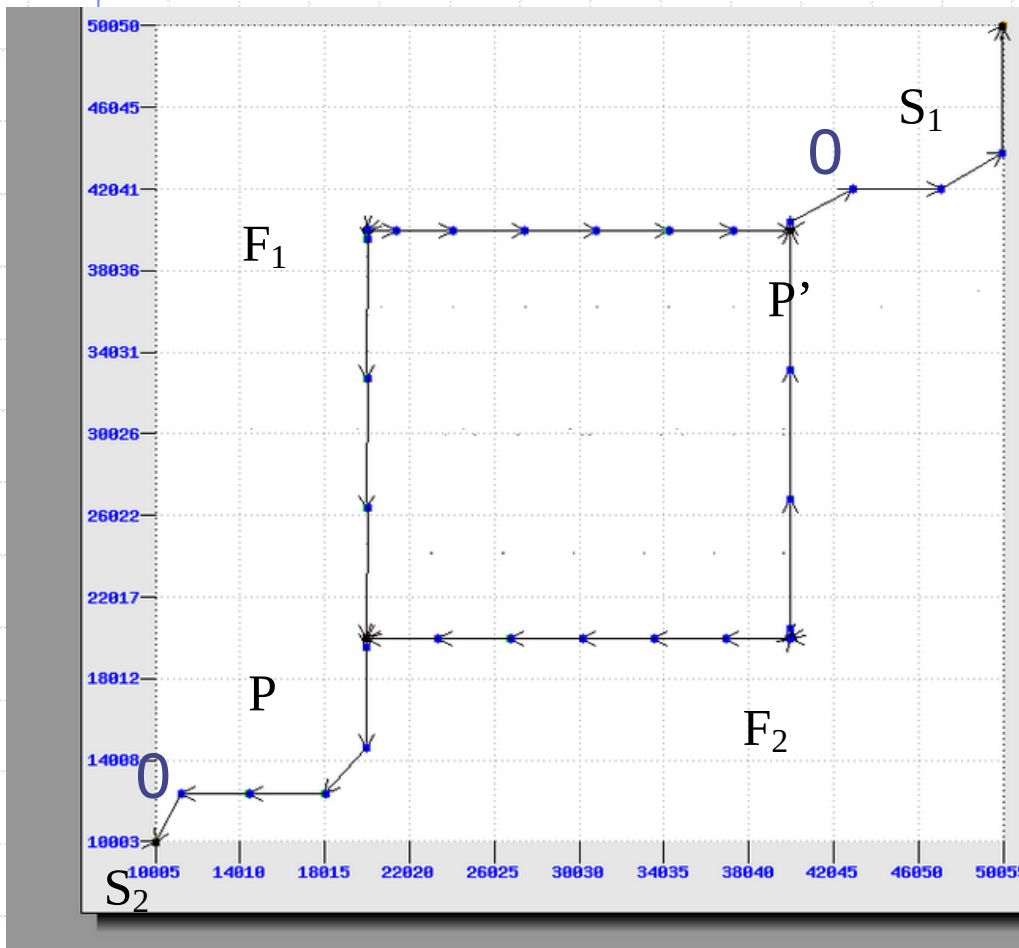
P is fixed



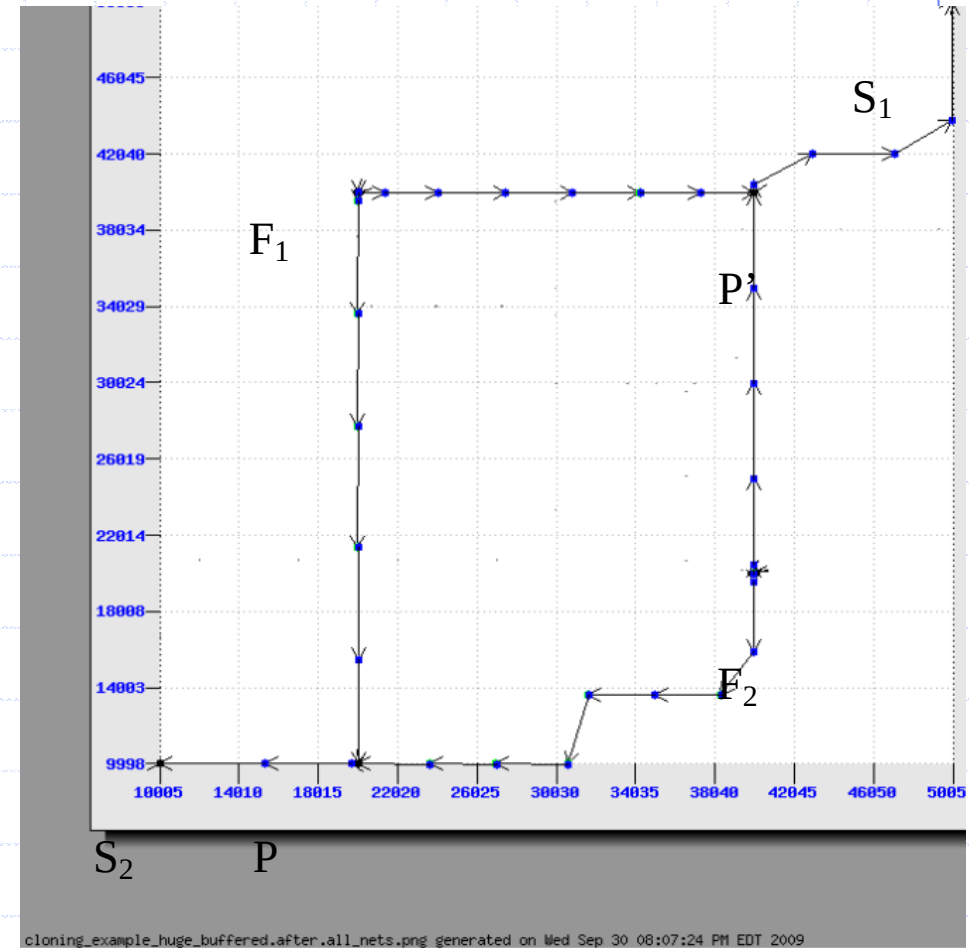


One Example

P is movable



Bad wavelength solution





Experimental Results

- ◆ 100 random 65 nm sub-circuits
 - P is fixed: 279 ps better than pure buffering, 87 ps better than RUBMLE on average
 - P is movable: 309 ps better than pure buffering, 117 ps better than RUMBLE on average

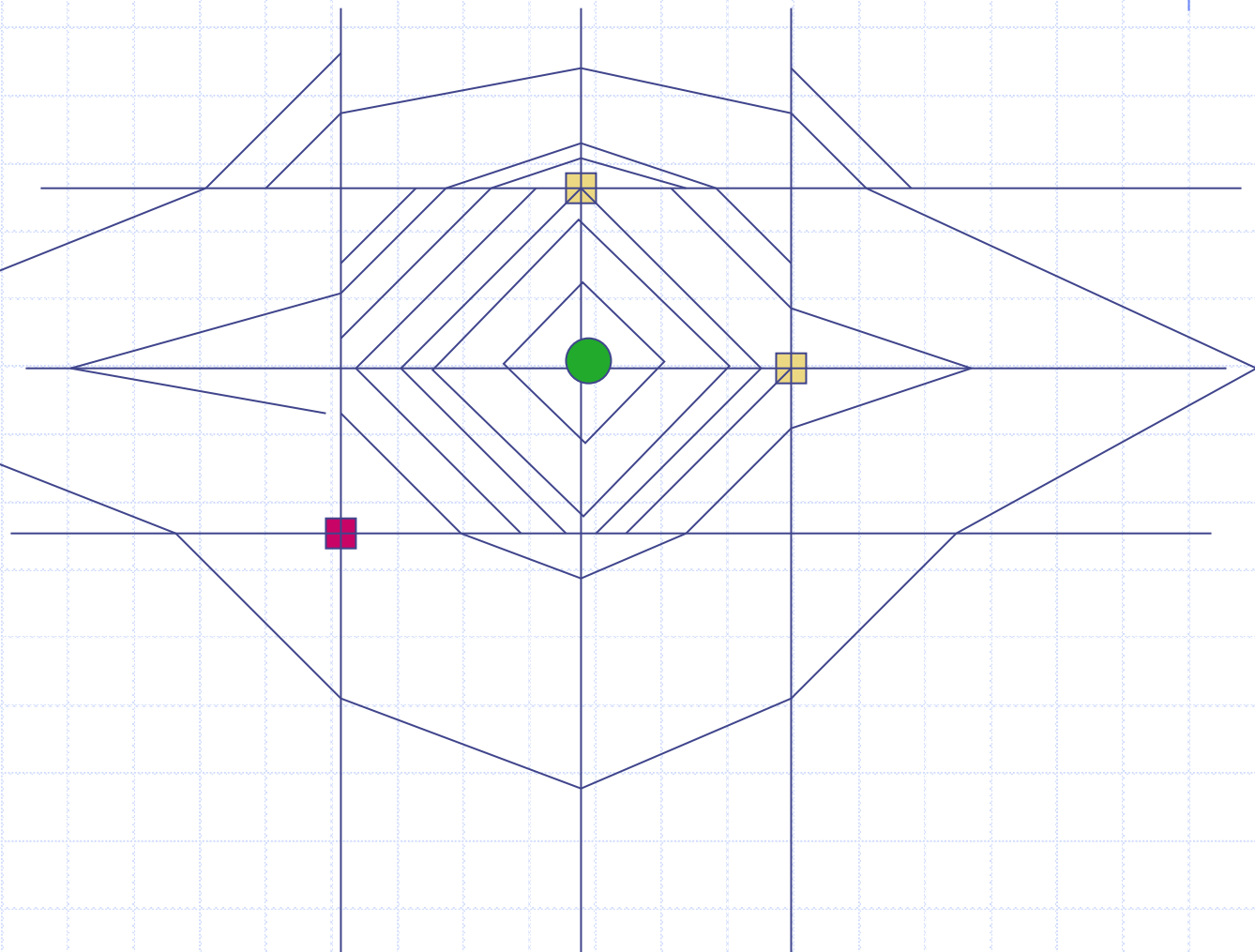
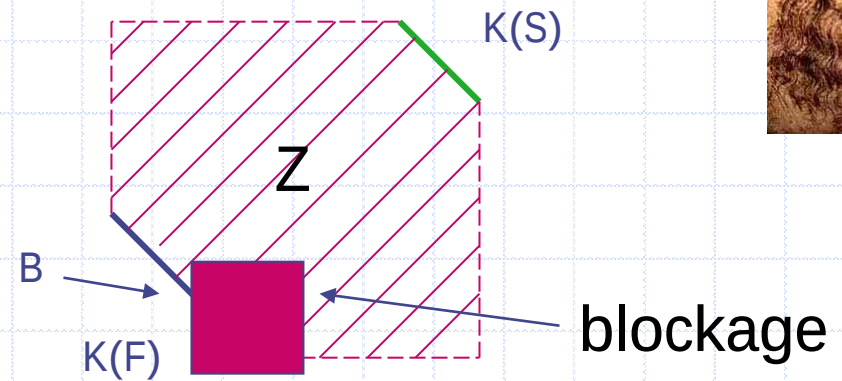
65 nm macros	# objs	Single transform		Compare to a flow with pure buffering		Area Increase
		Slack Imprv.	FOM Imprv.	Slack Imprv.	FOM Imprv.	
Macro 1	91k	0.480 ns	438	0.097 ns	-8	0.5%
Macro 2	231k	0.098 ns	0	0.081 ns	200	0.8%
Macro 3	191k	0.383 ns	2837	0.124 ns	280	1%



Extensions

- ◆ Duplicate more than two gates
 - $O(n^2)$ algorithm

- ◆ Be smart about Z regions
 - Latches
 - Blockages
 - Wire-length
 - FOM extension





Voronoi Diagram Partitioning

- ◆ Best slack for every sink with blockages
- ◆ If we know the locations of P and P'
 - The optimal partitioning is the Voronoi diagram between two points or a point and a diamond in Manhattan space
 - Only $O(n^3)$ possible partitionings
 - Try all partitionings and find the best one

